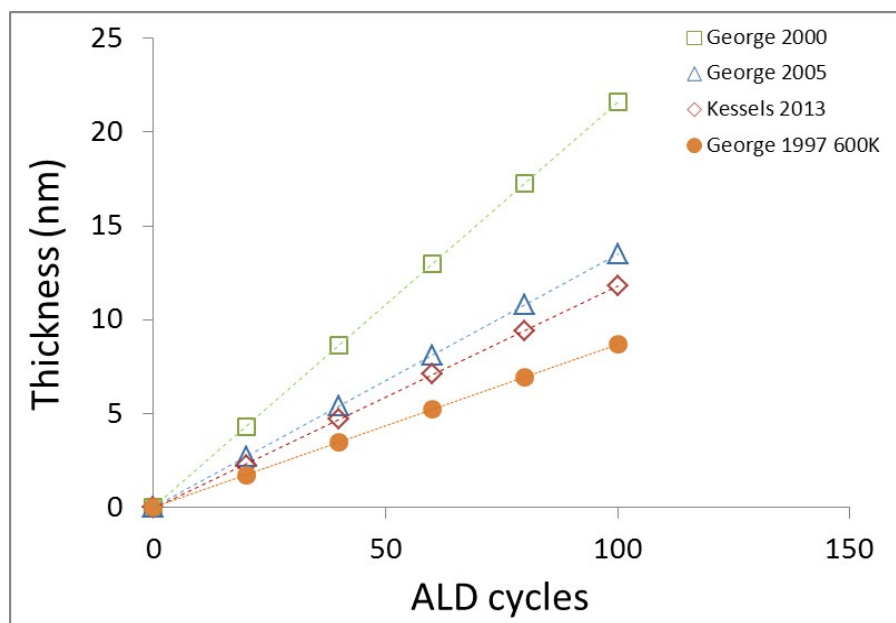


## SiO<sub>2</sub> thin film growth through a pure Atomic Layer Deposition at Room-Temperature

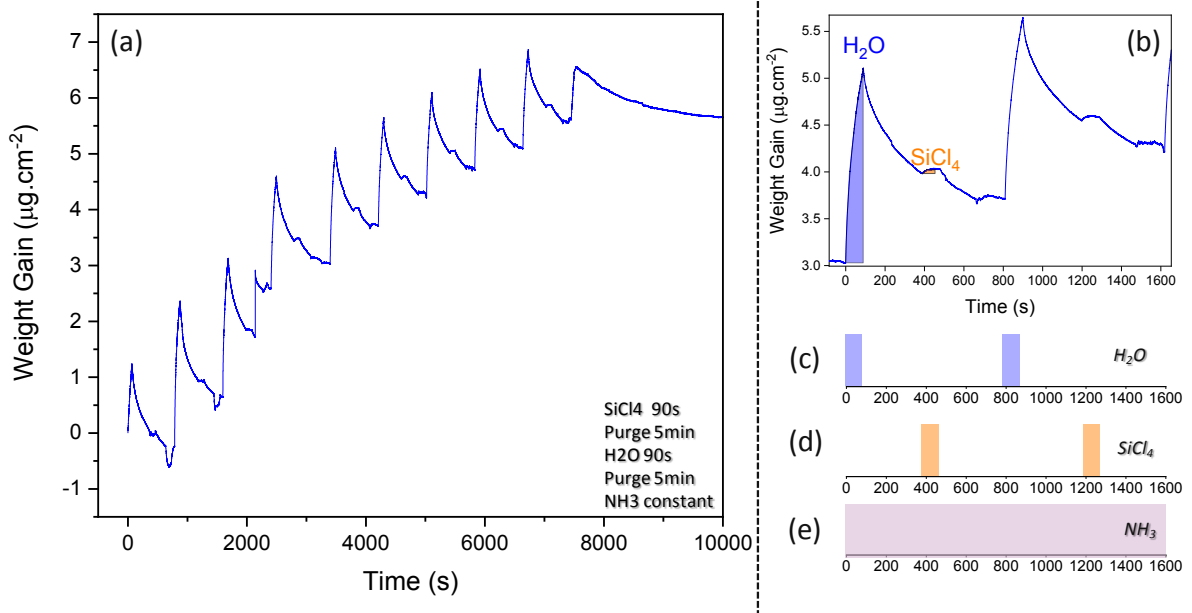
### Supporting information

S1:



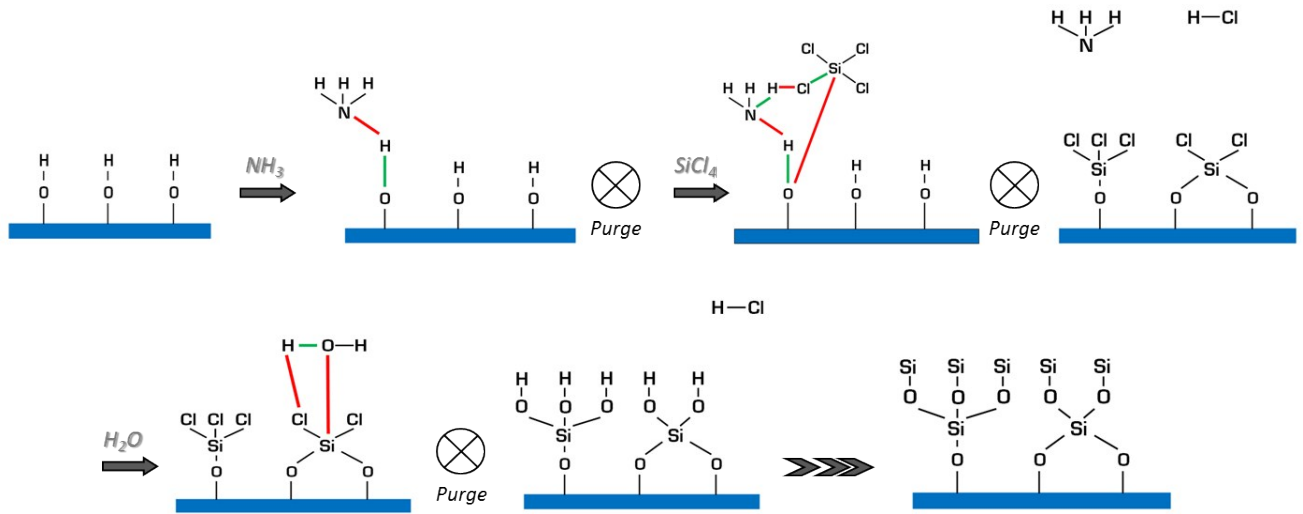
Evolution of SiO<sub>2</sub> film thickness as a function of ALD cycles based on the literature. All processes display a linear evolution with the number of cycles at room temperature [41,42,66] as well as high temperatures (600 K) [67].

S2:



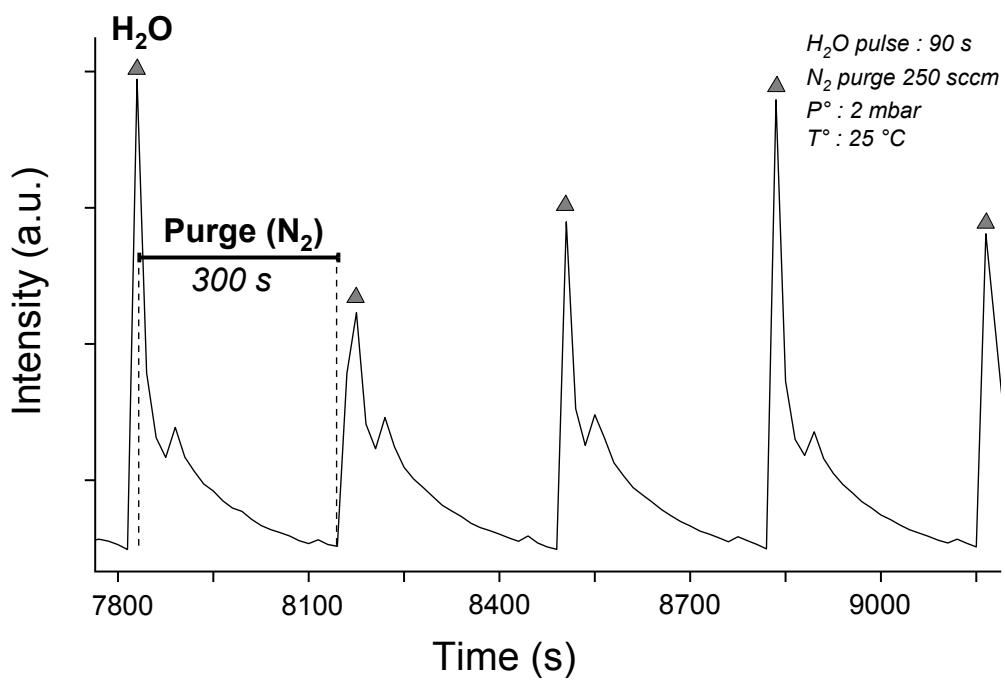
Growth kinetics of  $\text{SiO}_2$  for sequential exposure of the surface to 90s of  $\text{SiCl}_4$  and 90s of  $\text{H}_2\text{O}$ , indicating a growth rate of  $0.6 \mu\text{g}\cdot\text{cm}^{-2}$  per cycle. Panel (a) shows a typical zoom on 10 cycles of the total 2000 cycles deposited film. Panel (b) corresponds to the view of 2 cycles deposition. Lower panels represent the programmed exposures of  $\text{H}_2\text{O}$  (c),  $\text{SiCl}_4$  (d) and  $\text{NH}_3$  (e).

S3:



ALD room temperature growth of SiO<sub>2</sub> under NH<sub>3</sub> catalytic regime. Through the injection of NH<sub>3</sub>, the O-H bond becomes weaker, -Si can easily react with -O at the surface to form -O-Si-(Cl)<sub>3</sub> or -O-Si(Cl)<sub>2</sub>-O- ligands at the surface. -O coming from water injection directly react with -Si to finally form a SiO<sub>2</sub> monolayer.

S4:



*In-situ* RGA mass spectrometric monitoring of successive 90s H<sub>2</sub>O pulses alternated with 300s N<sub>2</sub> purge. The panel corresponds to the measured intensity of H<sub>2</sub>O ( $m/z = 18$  uma).

S5:

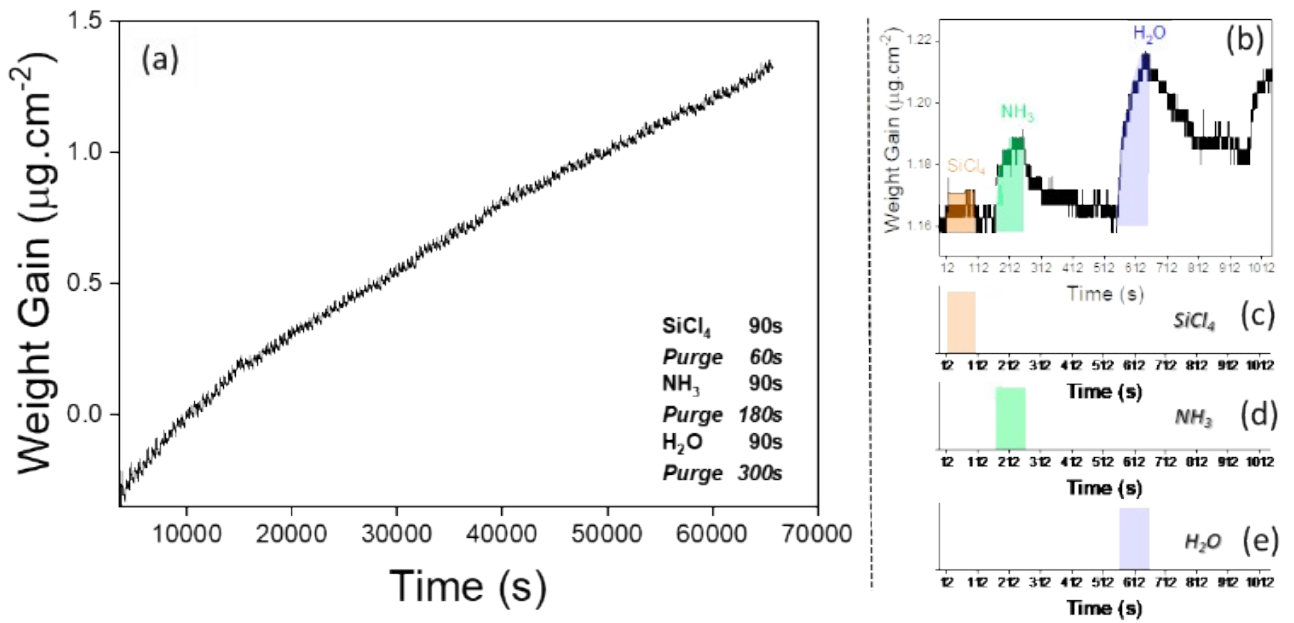
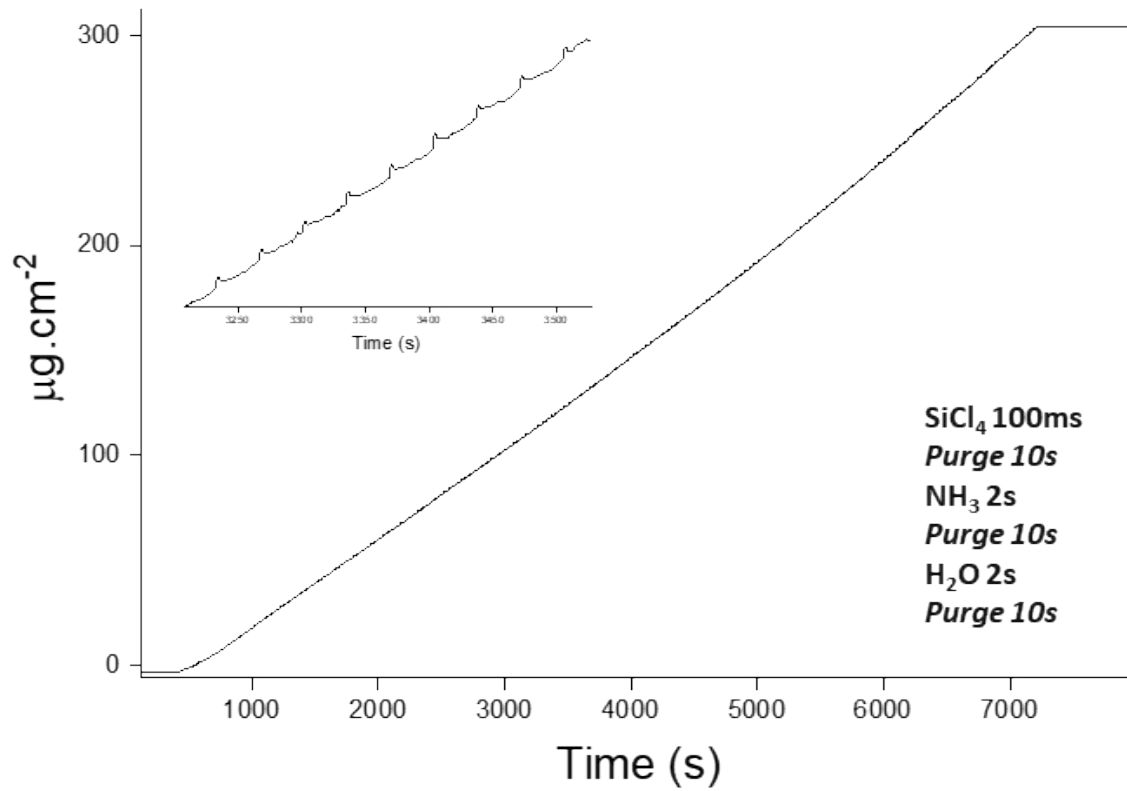


Fig. 5: Growth kinetics of pure ALD SiO<sub>2</sub> film with sequential exposure of the surface to 90s of SiCl<sub>4</sub>, 90s of NH<sub>3</sub> and 90s of H<sub>2</sub>O. (a) A typical zoom of the in situ monitoring of 500 loops deposition showing a growth rate of 0.02 µg.cm<sup>-2</sup> per cycle. The panel (b) represents a zoom of the 60% advanced deposition. Lower panels represent the programmed exposures of SiCl<sub>4</sub> (c) NH<sub>3</sub> (d) and H<sub>2</sub>O (e).

S6:



Growth kinetics of porous SiO<sub>2</sub> grown with sequential exposure of the surface to 100 ms of SiCl<sub>4</sub>, 2s of NH<sub>3</sub> and 2s of H<sub>2</sub>O. The in situ monitoring of 300 loops deposition corresponds to a growth rate of 1.5  $\mu\text{g}\cdot\text{cm}^{-2}$  per cycle. The insert represents a zoom of 10 cycles process.